

<b>Notice of References Cited</b>	Application/Control No. 10/596,966		Applicant(s)/Patent Under Reexamination SATO, HIDEO	
	Examiner QUANG PHAM		Art Unit 2612	Page 1 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,189,712 A	02-1980	Lemelson, Jerome H.	340/5.62
*	B	US-6,018,581 A	01-2000	Shona et al.	380/46
*	C	US-6,111,506 A	08-2000	Yap et al.	340/572.1
*	D	US-2001/0017584 A1	08-2001	Shinzaki, Takashi	340/5.52
*	E	US-2001/0033220 A1	10-2001	Stone et al.	340/5.52
*	F	US-2001/0029488 A1	10-2001	Takeshima et al.	705/41
*	G	US-2001/0038422 A1	11-2001	Yamada et al.	348/478
*	H	US-2001/0054951 A1	12-2001	Kimoto et al.	340/5.53
*	I	US-2002/0025046 A1	02-2002	Lin, Hung-Yu	380/282
*	J	US-2002/0018569 A1	02-2002	Panjwani et al.	380/247
*	K	US-2002/0024419 A1	02-2002	Dunn, Christopher S.	340/5.52
*	L	US-2002/0120668 A1	08-2002	Pintsov et al.	709/200
*	M	US-2002/0154779 A1	10-2002	Asano et al.	380/277

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/596,966		Applicant(s)/Patent Under Reexamination SATO, HIDEO	
	Examiner QUANG PHAM		Art Unit 2612	Page 2 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0166047 A1	11-2002	Kawamoto, Youji	713/169
*	B	US-6,476,715 B1	11-2002	Bromer, Nick	340/468
*	C	US-2002/0169971 A1	11-2002	Asano et al.	713/193
*	D	US-2002/0197979 A1	12-2002	Vanderveen, Michaela Catalina	455/410
*	E	US-2003/0018522 A1	01-2003	Denimarck et al.	705/14
*	F	US-2003/0048173 A1	03-2003	Shigematsu et al.	340/5.52
*	G	US-2003/0088618 A1	05-2003	Sueyoshi et al.	709/203
*	H	US-2003/0145203 A1	07-2003	Audebert et al.	713/169
*	I	US-2003/0167398 A1	09-2003	Sueyoshi et al.	713/189
*	J	US-2003/0167207 A1	09-2003	Berardi et al.	705/16
*	K	US-2003/0228886 A1	12-2003	Ishii et al.	455/558
*	L	US-6,672,512 B2	01-2004	Bridgelall, Raj	235/462.46
*	M	US-2004/0022421 A1	02-2004	Endoh et al.	382/115

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/596,966		Applicant(s)/Patent Under Reexamination SATO, HIDEO	
	Examiner QUANG PHAM		Art Unit 2612	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0041690 A1	03-2004	Yamagishi, Junichi	340/005.52
*	B	US-2004/0059925 A1	03-2004	Benhammou et al.	713/189
*	C	US-2004/0059685 A1	03-2004	Sakamura et al.	705/065
*	D	US-2004/0098587 A1	05-2004	Sueyoshi et al.	713/169
*	E	US-2004/0193898 A1	09-2004	Ochi et al.	713/189
*	F	US-2004/0208632 A1	10-2004	Dietz et al.	398/182
*	G	US-6,813,010 B2	11-2004	Kono et al.	356/71
*	H	US-2004/0259499 A1	12-2004	Oba et al.	455/041.2
*	I	US-2004/0239481 A1	12-2004	Beenau et al.	340/005.53
*	J	US-2004/0268131 A1	12-2004	Kudo et al.	713/182
*	K	US-2005/0010769 A1	01-2005	You et al.	713/168
*	L	US-2005/0061875 A1	03-2005	Zai et al.	235/383
*	M	US-2005/0076212 A1	04-2005	Mishina et al.	713/168

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/596,966		Applicant(s)/Patent Under Reexamination SATO, HIDEO	
	Examiner QUANG PHAM		Art Unit 2612	Page 4 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0081035 A1	04-2005	Togawa, Atsushi	713/171
*	B	US-2005/0086479 A1	04-2005	Ondet et al.	713/172
*	C	US-2005/0102527 A1	05-2005	Tatebayashi et al.	713/189
*	D	US-2005/0114619 A1	05-2005	Matsuo et al.	711/170
*	E	US-2005/0108522 A1	05-2005	Guthery, Scott B.	713/159
*	F	US-2005/0173518 A1	08-2005	Takayama, Hisashi	235/380
*	G	US-2005/0212657 A1	09-2005	Simon, Rudy	340/005.74
*	H	US-2005/0210249 A1	09-2005	Lee et al.	713/168
*	I	US-2006/0050877 A1	03-2006	Nakamura, Mitsuhiro	380/046
*	J	US-7,047,408 B1	05-2006	Boyko et al.	713/169
*	K	US-2006/0265735 A1	11-2006	Ohno, Chiyo	726/002
*	L	US-2007/0294528 A1	12-2007	Shoji et al.	713/159
*	M	US-7,644,265 B2	01-2010	Kudo et al.	713/150

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.